

Study on upper limit of sample size for a two-level test in NIST SP800-22

Hiroshi Haramoto

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Abstract NIST SP800-22 is one of the most widely used statistical testing tools for pseudorandom number generators (PRNGs). This tool consists of 15 tests (one-level tests) and two additional tests (two-level tests). Each one-level test provides one or more p -values. The two-level tests measure the uniformity of the obtained p -values for a fixed one-level test. One of the two-level tests categorizes the p -values into ten intervals of equal length, and apply a chi-squared goodness-of-fit test. This two-level test is often more powerful than one-level tests, but sometimes it rejects even good PRNGs when the sample size at the second level is too large, since it detects approximation errors in the computation of p -values.

In this paper, we propose a practical upper limit of the sample size in this two-level test, for each of six tests appeared in SP800-22. These upper limits are derived by the chi-squared discrepancy between the distribution of the approximated p -values and the uniform distribution $U(0, 1)$. We also computed a “risky” sample size at the second level for each one-level test. Our experiments show that the two-level test with the proposed upper limit gives appropriate results, while using the risky size often rejects even good PRNGs.

We also propose another improvement: to use the exact probability for the ten categories in the computation of goodness-of-fit at the two-level test. This allows us to increase the sample size at the second level, and would make the test more sensitive than the NIST’s recommending usage.

Keywords Statistical testing · Pseudorandom number generators · NIST SP800-22 · Two-level test

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H. Haramoto
Faculty of Education, Ehime University, 3 Bunkyocho, Matsuyama, Ehime 790-8577, Japan
E-mail: haramoto@ehime-u.ac.jp

1 Introduction

Statistical testing is a common way to evaluate whether the outputs of a pseudorandom number generator (PRNG) imitate independent random variables from the uniform distribution over the interval $[0, 1]$, or over the integers in an interval (e.g. $\{0, 1\}$).

There are many statistical tests for PRNGs, for example, TestU01 by L'Ecuyer and Simard is the most comprehensive test suite [12], and recently PractRand [2] has been published. In this paper, we investigate a test suite, named SP800-22, that is proposed by National Institute of Standards and Technology (NIST) [1] for pseudorandom bit generators (PRBGs). NIST SP800-22 is a standard test suite, especially in cryptography. This suite consists of 15 tests called one-level tests and two additional tests called two-level tests. One of the two-level tests categorizes the p -values into ten equal-length subintervals of $[0, 1]$, and apply a chi-squared goodness-of-fit (GOF) test. This two-level test permits us to apply the test with a larger total sample size, and hence, it is often more powerful than one-level tests. On the other hand, the two-level test tends to reject even good PRNGs because of approximation errors in computation of the p -values at the first level. Hence giving upper limit of sample size at the second level makes the two-level test more reliable: we can maximize the power and avoid erroneous rejections of the two-level test. Further descriptions and explanations of two-level tests can be found in [4, 8, 9, 10, 11, 16, 17, 20].

However, NIST recommends that the sample size at the second level should be on the order of the inverse of the significance level, without any mathematical justifications. Pareschi et al. [17] give the upper limit of the two-level test for the Frequency test and the Runs test in NIST SP800-22. Their research is based on Berry-Esséen inequality [18], but it seems difficult to derive upper limits of the other one-level tests. By contrast, we propose a practical upper limit of the sample size at the second level for each of the Frequency test, the Binary Matrix Rank test and the Runs test [5]. Those upper limits are derived by the chi-squared discrepancy between the distribution of approximated p -values and the uniform distribution. For example, we show that the upper limit of sample size at the second level test for the Frequency test is approximately 125,000 when the sample size at the first level is 10^6 . This value is larger than that recommended by NIST, which is 10^3 – 10^4 . We also show that the upper limits increase the power of the two-level test.

The aim of this paper is to extend the previous work [5], in particular, we propose a practical upper limit of the sample size at the second level for each of the following six tests in NIST SP800-22: the Longest-Run-of-Ones in a Block, the Overlapping Template Matching test, the Linear Complexity test, the Random Excursions test, the Frequency test within a Block, and the Discrete Fourier Transform test. The results indicate that appropriate upper limits heavily depend on the one-level tests and sample sizes at the first level.

The rest of this paper is organized as follows. In Section 2, we review the test suite NIST SP800-22 and the chi-squared discrepancy, and explain how to determine the upper limits of the sample size at the second level. In Section

3, we present upper limits of several tests and experimental results. In Section 4, we give an approximation of the distribution of p -values of one-level tests using a Monte Carlo simulation. In Section 5, we propose another improvement using the exact probability for the ten categories in the computation of the GOF in the two-level test.

2 Two-level test in NIST SP800-22 and chi-squared discrepancy

In this section, we briefly explain NIST SP800-22 and the chi-squared discrepancy.

NIST SP800-22 consists of 15 statistical tests called one-level tests. Each one-level test looks for empirical evidence against a null hypothesis $\mathcal{H}_{0,first}$ that random variables B_1, B_2, \dots, B_n are i.i.d. over the two-element set $\{0, 1\}$, i.e.,

$$\mathcal{H}_{0,first} : B_1, \dots, B_n \sim_{i.i.d.} \text{Binom}(1, 1/2).$$

Let T be a statistic of a statistical test. When testing the randomness, we assume that the distribution of T under $\mathcal{H}_{0,first}$ is known or well-approximated by a computable formula. We denote by F the cumulative distribution function of T . For a realization $(b_1, \dots, b_n) \in \{0, 1\}^n$, where b_i is the i -th output of the tested PRBG, the test rejects $\mathcal{H}_{0,first}$ and the PRBG if the probability (called the p -value)

$$\mathbb{P}(T(b_1, \dots, b_n) \leq T(B_1, \dots, B_n)) = 1 - F(T(b_1, \dots, b_n))$$

is much too close to either 0 or 1; we call n the first sample size.

If the p -value is very small (e.g. $< 10^{-10}$), then it is clear that the PRBG fails the test. However, if the p -value is suspicious but does not clearly indicate rejection (e.g. $\approx 10^{-4}$), it is difficult to judge.

In order to avoid such difficulties, a two-level test is often used. We fix a one-level test. At the first level, we apply the one-level test N times to disjoint parts of a sequence generated by the PRBG, yielding N p -values. At the second level, we compare the empirical distribution of those p -values to the expected distribution via a GOF test; we call N the second sample size.

NIST SP800-22 includes two two-level tests. In this paper we investigate the test referred to as the uniformity test, which is detailed below. Let ν be a positive integer. We denote by I_0, \dots, I_ν the subintervals of $[0, 1]$ defined by the following:

$$I_i := [i/(\nu + 1), (i + 1)/(\nu + 1)) \quad (i = 0, 1, \dots, \nu - 1), \text{ and} \\ I_\nu := [\nu/(\nu + 1), 1].$$

Let Y_i be the number of p -values that fall in the subinterval I_i , $i = 0, \dots, \nu$. If the random vector (Y_0, \dots, Y_ν) conforms to $\text{Multi}(N; p_0, \dots, p_\nu)$, the multinomial distribution with N trials and probability (p_0, \dots, p_ν) , then the chi-squared statistic

$$\chi^2 := \sum_{i=0}^{\nu} \frac{(Y_i - Np_i)^2}{Np_i}$$

approximately conforms to the chi-squared distribution with ν degrees of freedom for large N .

It is often assumed that the distribution of the p -values of a one-level test is uniform over $[0, 1]$. (Note that this is incorrect if T comes from a discrete probability distribution.) Under this uniformity assumption, the two-level test examines a null hypothesis

$$\mathcal{H}_{0,second} : p_0 = 1/(\nu + 1), \dots, p_\nu = 1/(\nu + 1).$$

For a realization χ_{obs}^2 of χ^2 , NIST SP800-22 defines the p -value at the second level by $\mathbb{P}(\chi_{obs}^2 \leq X)$, where X is a random variable that conforms to the chi-squared distribution with ν degrees of freedom. If the p -value at the second level is less than a pre-specified significance level, then we reject $\mathcal{H}_{0,second}$ and the PRBG.

Two-level tests are said to be more sensitive than one-level tests. However, such tests may lead to erroneous rejection, which is explained as follows: all the 15 one-level tests in NIST SP800-22 approximately compute p -values using continuous distributions instead of the actual discrete distributions. For example, the test statistic of the Frequency test in NIST SP800-22, conforms to a binomial distribution, but the test computes approximated p -values using a normal distribution. As a result, the probability q_i that the approximated p -values fall in the interval I_i differs from $1/(\nu + 1)$. The test statistic χ^2 has a larger deviation if N is larger, and the null hypothesis $\mathcal{H}_{0,second}$ is more likely to be rejected.

In order to decide an upper limit of second sample size, we here quantify the discrepancy between the distribution of approximated p -values of a one-level test $\{q_i\}$ and the null distribution $\{p_i\}$ under $\mathcal{H}_{0,second}$. Assume that (Y_0, \dots, Y_ν) actually conforms to $Multi(N; q_0, \dots, q_\nu)$, but tested by a chi-squared GOF test, assuming the null hypothesis that (Y_0, \dots, Y_ν) conforms to $Multi(N; p_0, \dots, p_\nu)$. In this case, Matsumoto and Nishimura [14] showed the following inequality:

$$|E(\chi^2) - (\nu + N\delta)| \leq \nu \max_{i=0,1,\dots,\nu} \left| 1 - \frac{q_i}{p_i} \right|. \quad (1)$$

Here a distance-like function

$$\delta := \sum_{i=0}^{\nu} \frac{(q_i - p_i)^2}{p_i}$$

refers to the chi-squared discrepancy of $\{q_i\}$ from $\{p_i\}$. Note that the chi-squared statistic χ^2 is known to conform to the noncentral chi-squared distribution having ν degrees of freedom with noncentrality parameter $N\delta$ [19].

Inequality (1) implies that χ^2 value is shifted by $N\delta$ in average. In addition, the expectation of χ^2 corresponds to the p -value $\alpha \in (0, 1)$ when

$$N \approx \frac{\chi_\nu^2(\alpha) - \nu}{\delta},$$

where $\chi_\nu^2(\alpha)$ is the upper 100α -th percentile of the chi-squared distribution with ν degrees of freedom for α .

In this paper, we only deal with the case $\nu = 9$ and the significance level 0.0001, which are initial values in NIST SP800-22. Let

$$u = \max_{i=0,\dots,\nu} \left| 1 - \frac{q_i}{p_i} \right|.$$

The two-level test with the second sample size

$$N_{0.0001} := \left\lceil \frac{\chi_\nu^2(0.0001) - \nu + u\nu}{\delta} \right\rceil$$

tends to reject PRBGs even if the tested PRBGs are ideal: at the sample size $N_{0.0001}$, the expectation of the χ^2 -value corresponds to the p -value

$$\mathbb{P}(N_{0.0001}\delta + \nu - u\nu \leq X) \approx 0.0001,$$

where X is a random variable conforming to the chi-squared distribution with ν degrees of freedom. On the other hand, if we take

$$N_{0.25} := \left\lceil \frac{\chi_\nu^2(0.25) - \nu - u\nu}{\delta} \right\rceil$$

as the second sample size, such erroneous rejections are unlikely to occur: the expectation of the χ^2 -value corresponds to the p -value

$$\mathbb{P}(N_{0.25}\delta + \nu + u\nu \leq X) \approx 0.25.$$

For these reasons, $N_{0.0001}$ and $N_{0.25}$ are called the risky sample size and the safe sample size at the second level, respectively, in [14]. The name “safe sample size” is somehow misleading, since the Inequality (1) implies that the distribution of χ^2 is considerably different from a chi-squared distribution even if one takes $N_{0.25}$ as the second sample size, and hence the probability of an erroneous rejection for an ideal random number generator is higher than a pre-specified significance level. Indeed, a numerical computation based on the noncentral chi-squared distribution shows that if the significance level is set to be 0.0001 (the default value for NIST tests) with degree of freedom 9, the probability of rejection due to too high χ^2 -value is about 0.001205194, which is much higher than 0.0001. However, if the NIST test procedure is used as it is, the probability of the rejection is around 0.0012, which would not result in the rejection of an ideal generator. The name “safe” means only in this context: the safe sample size is a thumb nail for the upper limit of the second sample size for the NIST test procedure.

3 Computing the distributions of p -values of some statistical tests

Three tests in SP800-22 based on chi-squared test. First, we consider the two-level test for the following three one-level tests: the test for the Longest-Run-of-Ones in a Block, the Overlapping Template Matching test, and the Linear Complexity test. Note that we apply a modification to the test for the Longest-Run-of-Ones in a Block to improve the approximation of p -values [6].

Below, we explain the common structure of these one-level tests. Each one-level test divides the n -bit sequence into $n_b = \lfloor n/m \rfloor$ blocks P_1, \dots, P_{n_b} of m bits. According to a certain property which the test investigates, the test classifies P_i 's into $k+1$ classes C_0, \dots, C_k . Let X_0, \dots, X_k be the numbers of the blocks classified in C_0, \dots, C_k , respectively. The test compares an observed frequency $\mathbf{X} = (X_0, \dots, X_k)$ to the theoretical one: NIST describes that the theoretical distribution of \mathbf{X} is $Multi(n_b; \pi_0, \dots, \pi_k)$ explicitly [1]. The test statistic of the one-level test is

$$T(\mathbf{X}) = T(X_0, \dots, X_k) := \sum_{i=0}^k \frac{(X_i - n_b \pi_i)^2}{n_b \pi_i}. \quad (2)$$

Let us denote by S the set of the realizations of \mathbf{X} , i.e.,

$$S = \left\{ \mathbf{x} = (x_0, \dots, x_k) \in \mathbb{Z}_{\geq 0}^{k+1} \mid x_0 + \dots + x_k = n_b \right\}. \quad (3)$$

For a realization $\mathbf{x} \in S$, the one-level test approximates its p -value by $\mathbb{P}(T(\mathbf{x}) \leq X)$, where X is a random variable that follows the chi-squared distribution with k degrees of freedom. Therefore, the probability q_i that the approximated p -values fall in the subinterval I_i is

$$q_i = \sum_{\mathbf{x} \in S, \mathbb{P}(T(\mathbf{x}) \leq X) \in I_i} \frac{n_b!}{x_0! \dots x_k!} \pi_0^{x_0} \dots \pi_k^{x_k}, i = 0, 1, \dots, \nu.$$

Exhaustive computation derives the values of q_i 's. Table 1 shows the values of q_i 's, δ , $N_{0.25}$, and $N_{0.0001}$ when the first sample size is $n = 10^6$. The block size m is indicated in the second row of Table 1, and the other test parameters are the initial values in NIST SP800-22.

In order to justify the name of the risky/safe sample sizes, we apply the two-level test to Mersenne Twister (MT) [13] and a PRNG from the SHA-1 algorithm (SHA-1) with five different initial random seeds. We take the second sample sizes approximately $N_{0.25}$ and $N_{0.0001}$. We assume that both MT and SHA-1 are good generators, and thus the empirical distribution of χ^2 are expected to conform to the theoretical distribution described in Section 2. Because the Linear Complexity test always yields very small p -values when tested PRNGs have \mathbb{F}_2 -linearity, we apply the two-level test for the Linear Complexity test only to SHA-1.

Table 2 shows the resulting p -values of the two-level test. The table shows that $N_{0.0001}$'s yield small p -values, and then some rejections occur. On the other hand, $N_{0.25}$'s give no rejections at the second level.

Table 1 Values of q_i 's, δ , $N_{0.25}$ and $N_{0.0001}$ of three one-level tests

Test m	Longest 10,000	Overlap 1,032	Linear 5,000
q_0	0.0984739	0.0998142	0.0992755
q_1	0.0993067	0.0999758	0.0958139
q_2	0.1003668	0.1000190	0.0965409
q_3	0.1008263	0.1000541	0.0994559
q_4	0.1011301	0.1000879	0.1029601
q_5	0.1010720	0.1000979	0.1013597
q_6	0.1007868	0.1000902	0.1033444
q_7	0.1004239	0.1000561	0.1025969
q_8	0.0994782	0.0999548	0.1004993
q_9	0.0981354	0.0998500	0.0981534
δ	1.060097×10^{-4}	9.150630×10^{-7}	6.250910×10^{-4}
$N_{0.25}$	20,950	2,592,207	3,218
$N_{0.0001}$	234,769	27,032,746	40,149

Table 2 p -values of the two-level tests on MT and SHA-1

Test	PRNG	N	1st	2nd	3rd	4th	5th
Longest	MT	21,000	3.75e-01	5.76e-01	7.02e-02	9.76e-03	6.39e-01
		235,000	7.82e-03	6.93e-08	1.74e-08	1.05e-03	7.24e-07
	SHA-1	21,000	4.82e-01	7.64e-01	9.77e-01	5.48e-04	9.64e-01
		235,000	3.89e-04	9.18e-05	2.11e-02	2.41e-07	6.02e-05
Overlap	MT	2,600,000	1.47e-01	9.69e-01	1.41e-01	7.27e-02	4.01e-02
		27,033,000	1.17e-02	2.71e-03	1.12e-02	3.20e-03	8.53e-05
	SHA-1	2,600,000	2.00e-01	8.68e-02	4.36e-01	2.68e-02	6.02e-01
		27,033,000	1.26e-05	1.63e-05	1.14e-04	1.19e-03	1.08e-03
Linear	SHA-1	3,200	4.94e-01	9.18e-01	1.05e-01	1.96e-01	6.77e-02
		40,200	1.96e-03	1.40e-10	1.57e-05	7.38e-06	1.00e-04

The Random Excursions test. We consider the Random Excursions test. This test yields simultaneously eight p -values (one for each test parameter $x = \pm 1, \pm 2, \pm 3$ and ± 4) when the number of cycles J , which is determined by the tested sequence, is greater than or equal to 500, and yields no results when $J < 500$.

For the sake of simplicity, in this paper, we alter the test procedure slightly: when $J = 500$, the test yields eight p -values and discards the remaining bits, and when $J < 500$, the test yields no results.

Table 3 includes the results of exhaustive computation of q_i 's, etc. Tables 4 and 5 show the resulting p -values of this two-level test on MT and SHA-1, respectively.

4 Monte Carlo computation of the distributions of p -values

Although exhaustive computation can derive the exact value of q_i 's, it is impossible to carry out such a computation when the number of realizations is

Table 3 The values of q_i 's, δ , $N_{0.25}$ and $N_{0.0001}$ of the Random Excursions test

x	± 1	± 2	± 3	± 4
q_0	0.0994313	0.0993668	0.0989417	0.0986037
q_1	0.0992651	0.0989767	0.0976982	0.0959258
q_2	0.0999442	0.0998576	0.0994305	0.0984995
q_3	0.1006237	0.1000796	0.1005629	0.1005897
q_4	0.0999540	0.1006024	0.1005381	0.1014219
q_5	0.1006994	0.1006013	0.1014175	0.1016747
q_6	0.1007053	0.1006613	0.1010161	0.1026947
q_7	0.1001240	0.1004919	0.1014867	0.1011569
q_8	0.0998671	0.0998926	0.0994729	0.1013548
q_9	0.0993858	0.0994698	0.0994353	0.0980782
δ	2.654570×10^{-5}	3.171128×10^{-5}	1.319765×10^{-4}	4.010343×10^{-4}
$N_{0.25}$	87,494	72,423	16,530	5,042
$N_{0.0001}$	933,714	782,436	188,876	62,555

Table 4 p -values of the two-level test for the Random Excursions test on MT

x	N	1st	2nd	3rd	4th	5th
-4	5,000	1.85e-01	7.85e-01	1.12e-01	1.54e-01	3.28e-01
	63,000	3.14e-05	1.33e-04	9.75e-05	1.39e-06	2.01e-02
-3	16,500	2.03e-01	9.19e-01	1.36e-01	2.38e-01	7.51e-01
	190,000	4.00e-03	5.79e-03	5.64e-05	1.52e-05	1.11e-05
-2	72,000	4.18e-01	1.98e-01	2.05e-01	2.65e-02	5.68e-02
	783,000	9.96e-05	1.96e-05	7.50e-03	3.38e-08	6.24e-04
-1	87,000	2.85e-01	5.06e-01	5.59e-01	1.99e-01	7.06e-02
	934,000	5.22e-10	3.91e-05	2.59e-07	1.07e-08	2.63e-09
1	87,000	5.79e-01	5.98e-01	5.57e-01	2.98e-01	7.55e-01
	934,000	3.31e-07	9.59e-06	2.88e-04	4.01e-07	2.26e-07
2	72,000	2.07e-02	4.35e-01	3.94e-01	9.56e-01	3.39e-01
	783,000	3.91e-06	2.78e-09	9.24e-04	1.01e-03	3.92e-05
3	16,500	1.34e-01	2.68e-01	5.41e-01	1.02e-01	3.56e-02
	190,000	6.92e-05	3.82e-08	3.10e-07	7.69e-05	7.76e-09
4	5,000	4.54e-01	4.99e-02	4.44e-01	1.64e-01	8.52e-01
	63,000	3.70e-04	5.06e-03	1.05e-03	1.33e-04	6.69e-05

too large. For example, if we change the parameter of the above Linear Complexity test to $m = 500$, then the number of realizations is increased to be approximately 9.0×10^{16} , which is prohibitively large. For comparison, the number of realizations of the Overlapping Template Matching test is approximately 7.2×10^{12} , and the exact q_i 's of this test by exhaustive computation require 1,300 hours on an AMD Ryzen 7 1800X processor at 3.6 GHz with 16 GB of memory. We thus consider to approximate the values of q_i 's by a Monte Carlo simulation.

Let $\mathbf{x}_1, \dots, \mathbf{x}_M$ be i.i.d. random samples from the sample space S defined by Equation (3) in Section 3. We approximate the value q_i by

$$q'_i := \# \{j \mid \mathbb{P}(T(\mathbf{x}_j) \leq X) \in I_i, j = 1, \dots, M\} / M$$

for $i = 0, 1, \dots, \nu$, where T and X are defined in Section 3.

Table 5 p -values of the two-level test for the Random Excursions test on SHA-1

x	N	1st	2nd	3rd	4th	5th
-4	5,000	7.88e-01	2.16e-01	1.50e-02	1.28e-01	9.20e-03
	63,000	6.38e-06	4.90e-10	1.08e-02	4.41e-03	4.92e-07
-3	16,500	6.10e-02	6.61e-02	3.81e-01	8.15e-01	4.11e-01
	190,000	4.65e-07	2.50e-07	6.18e-03	5.47e-05	4.77e-05
-2	72,000	6.34e-01	5.55e-03	7.88e-01	3.89e-01	5.20e-01
	783,000	3.36e-06	3.81e-11	5.56e-05	9.00e-08	8.73e-04
-1	87,000	4.44e-01	1.38e-03	7.31e-01	5.50e-01	6.14e-01
	934,000	5.48e-11	8.58e-10	2.34e-08	1.72e-05	1.13e-03
1	87,000	5.67e-02	7.76e-01	6.82e-02	2.09e-01	2.93e-01
	934,000	9.77e-12	1.50e-09	5.04e-09	1.18e-04	3.65e-15
2	72,000	6.83e-04	1.77e-01	1.05e-02	2.34e-01	1.99e-01
	783,000	6.88e-11	5.54e-07	1.20e-04	8.55e-10	7.38e-05
3	16,500	8.06e-01	7.94e-01	1.12e-01	5.93e-01	2.15e-01
	190,000	1.77e-04	2.52e-03	5.37e-05	5.65e-08	3.11e-04
4	5,000	3.35e-01	2.97e-01	8.31e-02	2.69e-02	5.77e-01
	63,000	9.39e-06	8.48e-04	4.79e-06	1.03e-03	6.04e-08

Figures 1 and 2 show the results of the Monte Carlo simulation for computing the chi-squared discrepancy δ of $\{q'_i\}$ from $\{1/(\nu+1)\}$ and $u = \max_{i=0,\dots,\nu} |1 - q'_i/p_i|$ of the Linear Complexity test with parameter $m = 5,000$, respectively: we use the `gsl_ran_multinomial` function in the Gnu Scientific Library (GSL) to generate random samples $\mathbf{x}_1, \dots, \mathbf{x}_M$ [3]. According to these results, we estimate that $\delta = 4.625 \times 10^{-6}$ and $u = 4.442 \times 10^{-3}$, and hence $N_{0.25} \approx 507,809$ and $N_{0.0001} \approx 5,353,131$. Note that the standard deviations of δ and u in the experiment are 3.231×10^{-9} and 1.837×10^{-6} , respectively.

Table 6 shows the results of the two-level test with these second sample sizes on SHA-1.

Table 6 p -values of the two-level test for the Linear Complexity test ($m = 500$)

PRNG	N	1st	2nd	3rd	4th	5th
SHA-1	507,000	2.43e-03	7.24e-01	2.57e-01	8.61e-02	5.61e-02
	5,354,000	3.73e-14	3.19e-09	6.73e-08	3.25e-09	1.49e-11

The Frequency test within a Block. This test divides the given n -bit sequence into $n_b = \lfloor n/m \rfloor$ blocks of m bits. Let X_i be the number of ones in the i -th block for $i = 1, \dots, n_b$. Under $\mathcal{H}_{0,first}$, those X_1, \dots, X_{n_b} are i.i.d. binomial random variables with mean $m/2$ and variance $m/4$. The test computes a test statistic

$$T(X_1, \dots, X_{n_b}) := \sum_{i=1}^{n_b} \frac{(X_i - m/2)^2}{m/4} = 4m \sum_{i=1}^{n_b} (X_i/m - 1/2)^2$$

which should have approximately the chi-squared distribution with n_b degrees of freedom if m is large enough.

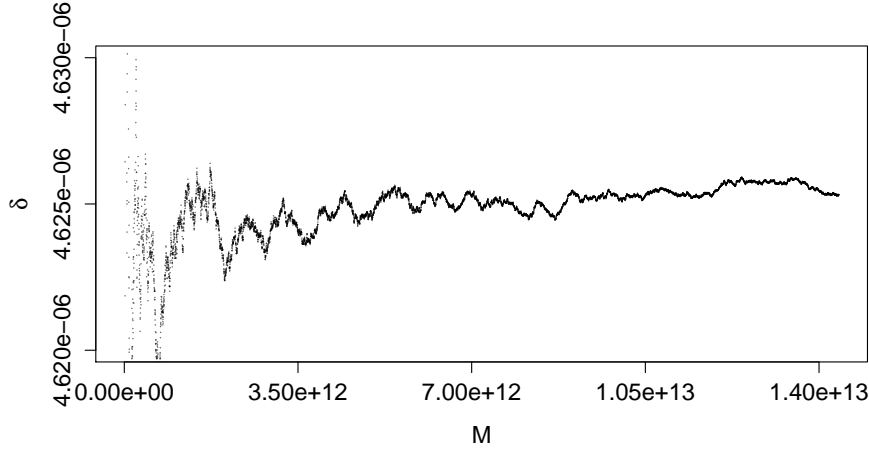


Fig. 1 Monte Carlo simulation for δ of the Linear Complexity test ($m = 500$)

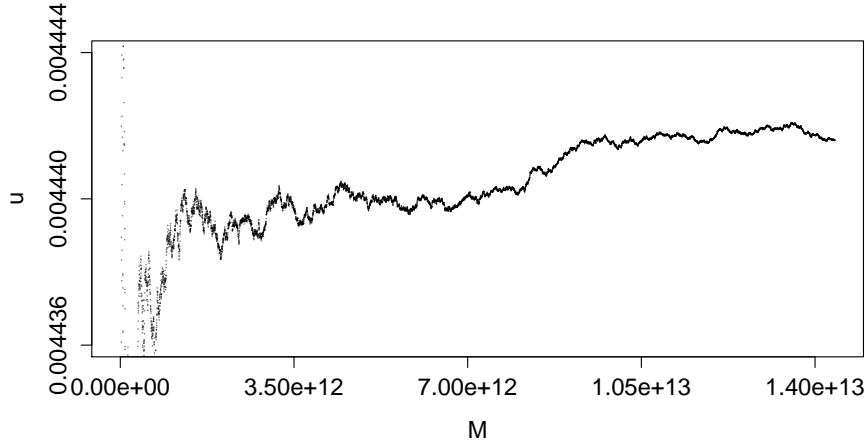


Fig. 2 Monte Carlo simulation for $\max_{i=0,\dots,\nu} |1 - q'_i/p_i|$ of the Linear Complexity test ($m = 500$)

The set of the realizations is $S = \{0, 1, \dots, m\}^{n_b}$ and consequently the total number of realizations is $(m + 1)^{n_b}$. NIST recommends that $m = 128$ and $n \geq 10^6$, but exhaustive computation seems impossible, so we conduct a Monte Carlo simulation: in this experiment, we generate random samples using the `gsl_ran_binomial` function in the Gnu Scientific Library.

From the results of the Monte Carlo simulation, we approximate that $\delta = 2.200 \times 10^{-5}$ and $u = 8.990 \times 10^{-2}$ (see Figures 3 and 4.) The standard deviations of δ and u are 1.728×10^{-8} and 3.775×10^{-6} , respectively, and $N_{0.25} \approx 71,802$ and $N_{0.0001} \approx 1,160,411$. Table 7 shows the results of the two-level test on MT and SHA-1.

These experimental results indicate that the Monte Carlo simulation gives good approximations of δ , q_i 's, and the risky/safe sample sizes.

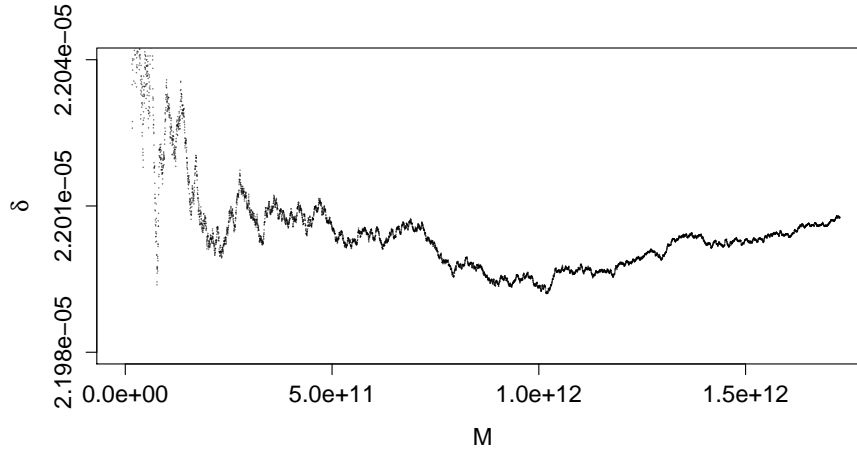


Fig. 3 Monte Carlo simulation for δ of the Frequency test within a Block ($m = 128$)

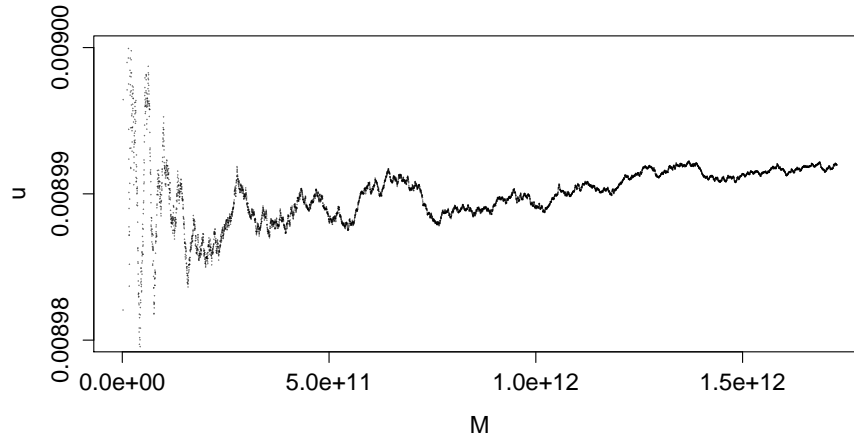


Fig. 4 Monte Carlo simulation for $\max_{i=0,1,\dots,\nu} |1 - q'_i/p_i|$ of the Frequency test within a Block ($m = 128$)

Table 7 p -values of the two-level test for the Frequency test within a Block ($m = 128$)

PRNG	N	1st	2nd	3rd	4th	5th
MT	71,800	3.06e-02	5.21e-04	5.64e-01	6.85e-01	4.68e-01
	1,161,000	8.20e-09	3.65e-06	6.44e-06	9.28e-06	1.80e-03
SHA-1	718,00	9.60e-01	7.21e-01	3.74e-01	6.51e-01	1.72e-01
	1,161,000	2.35e-04	1.06e-05	1.48e-03	9.52e-03	1.69e-07

The Discrete Fourier Transform (DFT) test. The purpose of this test is to detect periodic features in the tested sequence that would indicate a deviation from the assumption of randomness.

The first sample size n of the DFT test must be even. The discrete Fourier coefficients for the random bit variables B_k are defined by

$$F_i = \sum_{k=0}^{n-1} (2B_k - 1) \exp(-2\pi\sqrt{-1}ki/n)$$

for $i = 0, 1, \dots, n/2 - 1$. Let O_h denote the observed number of $|F_i|$'s that are smaller than a specified threshold h .

NIST SP800-22 falsely assumes that $|F_i|$'s are mutually independent. Under this assumption and when $h = \sqrt{2.995732274n}$, O_h is approximately a binomial random variable with $n/2$ trials and probability 0.95, and O_h has approximately the normal distribution with mean $\mu = 0.95n/2$ and variance $\sigma_0^2 = 0.05 \cdot 0.95n/2$. Hence, NIST SP800-22 defines the approximated p -value of the DFT test for a realization o_h of O_h by

$$\mathbb{P}(|o_h - \mu|/\sigma_0 < |X|) = 2(1 - \Phi(|o_h - \mu|/\sigma_0)),$$

where X is a random variable that conforms to the standard normal distribution $N(0, 1)$ and Φ is the cumulative distribution function of the standard normal distribution. Since o_h varies from 0 to $n/2$, we have

$$q_i = \sum_{0 \leq j \leq n/2, \mathbb{P}(|j - \mu|/\sigma_0 < |X|) \in I_i} \binom{n/2}{j} \times 0.95^j \times 0.05^{n/2-j}.$$

For the first sample size $n = 10^6$, we have $N_{0.25} = 18,690$, and $N_{0.0001} = 210,628$.

Actually, the approximation of O_h by the normal distribution $N(\mu, \sigma_0^2)$ is inaccurate, and there are many reports on defects of the DFT test. Indeed, NIST corrected the approximation of the variance to a better value $\sigma_1^2 = 0.05 \cdot 0.95n/4$ proposed by Kim et al. [7] from σ_0^2 . Later, Pareschi et al. [17] found a further good approximation value $\sigma_2^2 = 0.05 \cdot 0.95n/3.8$. According to [6], we use σ_2^2 for variance in the following experiments.

Next, we consider the following Monte Carlo simulation. Using MT, we generate M n -bit sequences and yield M p -values by the DFT test. We count the number of those p -values that fall in the interval I_i , $i = 0, 1, \dots, \nu$. Then we use this empirical distribution instead of the actual distribution.

Figures 5 and 6 show the results of the Monte Carlo simulations. We approximate δ by 5.438×10^{-4} and u by 3.679×10^{-2} using the Monte Carlo simulation with $M = 1.7 \times 10^{12}$ sequences: the standard deviations are 7.419×10^{-7} and 6.339×10^{-5} . The results are $N_{0.25} = 3,785$ and $N_{0.0001} = 46,084$. Table 8 shows the p -values of the two-level test with the second sample sizes of 3,700, 18,600, 46,100 and 211,000. In the experiments, we test on SHA-1 and WELL [15]: we avoid to test on MT because it is used for generating random sequences for approximating δ and u . These results indicate that the Monte Carlo simulation gives an approximation value of δ with enough accuracy in practical use.

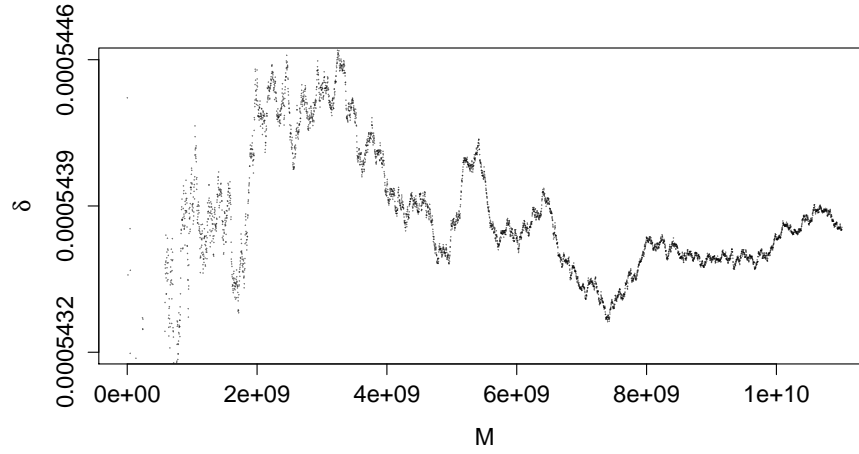


Fig. 5 Monte Carlo simulation for δ of the DFT test

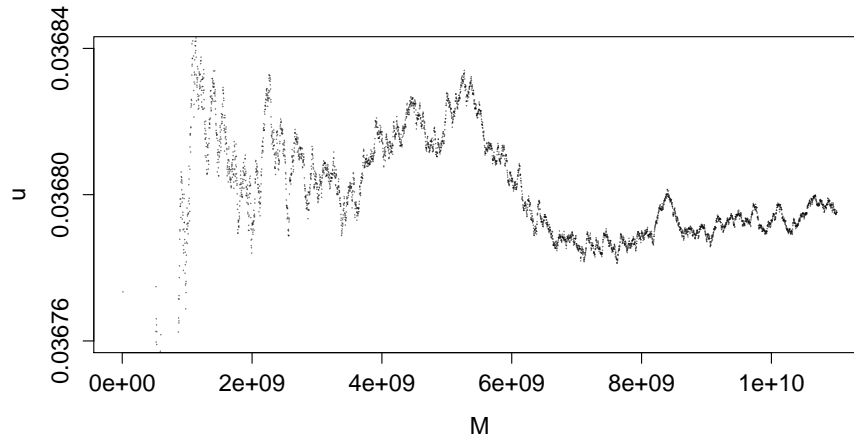


Fig. 6 Monte Carlo simulation for $\max_{i=0,1,\dots,\nu} |1 - q'_i/p_i|$ of the DFT test

Table 8 p -values of the two-level test for the DFT test

PRNG	N	1st	2nd	3rd	4th	5th
WELL	3,700	6.20e-01	1.58e-01	4.23e-03	2.28e-02	3.59e-01
	18,600	8.33e-02	4.22e-01	1.55e-01	3.20e-01	5.47e-01
	46,100	4.51e-03	6.00e-02	1.29e-02	2.06e-02	1.43e-01
	211,000	3.60e-22	9.00e-16	2.12e-18	9.13e-20	2.37e-14
SHA-1	3,700	8.75e-01	4.02e-01	5.07e-01	1.80e-01	3.77e-01
	18,600	1.06e-01	1.85e-01	6.71e-02	3.98e-08	4.67e-03
	46,100	5.46e-03	1.24e-03	2.07e-03	4.29e-06	9.41e-07
	211,000	6.36e-22	4.59e-22	2.18e-20	4.39e-25	3.94e-25

5 Improving two-level testing

As explained in Section 2, the two-level test under the null hypothesis

$$\mathcal{H}_{0,second} : p_0 = 1/(\nu + 1), \dots, p_\nu = 1/(\nu + 1),$$

tends to give erroneous rejections when the second sample size is too large. Consequently the second sample size must be limited and we recommend $N_{0.25}$ as an upper limit. This restriction is necessary but inconvenient.

However, if we use a null hypothesis

$$\mathcal{H}'_{0,second} : p_0 = q_0, \dots, p_\nu = q_\nu$$

where $\{q_i\}$ is the actual distribution of approximated p -values, then the chi-squared discrepancy δ becomes 0. This implies that we can increase the value of upper limit of the two-level test.

For example, in Section 3, we derived $\{q_i\}$ of the following four tests: the Longest-Run-of-Ones in a Block, Overlapping Template Matching test, Linear Complexity test with parameter $m = 5,000$, and the Random Excursions test. We then apply the two-level test under $\mathcal{H}'_{0,second}$ to MT and SHA-1.

Table 9 shows the p -values of several empirical results. The first sample size is $n = 10^6$, and the second sample size N is shown in the third column of Table 9. These N 's are approximately $N_{0.0001}$ or $2N_{0.0001}$: recall that $N_{0.0001}$ is the risky sample size under $\mathcal{H}_{0,second}$.

In the experiments, we observe that the p -values are moderate, thus these results are as we expected.

Table 9 p -values of the two-level test under $\mathcal{H}'_{0,second}$

Test	PRNG	N	1st	2nd	3rd	4th	5th
Longest	MT	500,000	9.36e-02	4.16e-01	9.48e-01	6.01e-01	5.84e-01
	SHA-1	500,000	5.91e-01	1.31e-01	2.96e-01	3.80e-01	5.19e-01
Overlap	MT	27,033,000	3.24e-02	2.58e-02	4.66e-03	5.83e-01	1.27e-01
	SHA-1	27,033,000	4.36e-01	4.29e-01	7.57e-01	2.87e-01	3.00e-04
Linear	SHA-1	100,000	7.42e-01	1.40e-01	4.00e-01	7.94e-01	2.51e-01

Table 10 shows the results of the two-level test for the Random Excursions test when $n = 10^6$ and $N = 2 \times 10^6$ under $\mathcal{H}'_{0,second}$. We show the p -value less than the significance level 0.0001 and test parameter x : the symbol “-” indicates that no rejection occurred.

The results indicate that, under $\mathcal{H}'_{0,second}$, the two-level test seems sufficiently accurate even if we take a larger sample size.

In Section 4, we approximate distributions of approximated p -values, say $\{q'_i\}$, using a Monte Carlo simulation. We consider to replace the null hypothesis $\mathcal{H}_{0,second}$ with

$$\mathcal{H}''_{0,second} : p_0 = q'_0, \dots, p_\nu = q'_\nu$$

Table 10 Results of the two-level test for the Random Excursions test under $\mathcal{H}'_{0,second}$

PRNG	N	1st	2nd	3rd	4th	5th
MT	2,000,000	-	-	-	-	-
SHA-1	2,000,000	3.77e-05 ($x = -3$)	-	-	-	1.27e-05 ($x = 1$)

to make upper limit of second sample sizes more flexible.

We apply the two-level test under $\mathcal{H}''_{0,second}$ to MT and SHA-1. The values of q'_i 's are presented in Table 11: these values are calculated by the Monte Carlo simulation described in Section 4. The first sample sizes is $n = 10^6$ and the second sample size N is indicated in the third column of Table 12. Similar to the previous experiments, we took $N_{0.0001}$ or $2N_{0.0001}$ as the second sample sizes.

Table 12 shows the p -values of the two-level test. From these results, the null hypothesis $\mathcal{H}''_{0,second}$ also allows us to take larger sample sizes.

Table 11 Values of q'_i 's by Monte Carlo simulation

Test	Linear ($m = 500$)	Block Freq.	DFT
q'_0	0.09985	0.09912	0.1012
q'_1	0.09956	0.09993	0.0987
q'_2	0.09983	0.10029	0.1023
q'_3	0.09999	0.10028	0.0964
q'_4	0.10016	0.10042	0.1015
q'_5	0.10026	0.10039	0.1012
q'_6	0.10025	0.10027	0.0963
q'_7	0.10017	0.10024	0.1014
q'_8	0.10009	0.09996	0.0979
q'_9	0.09984	0.09910	0.1031

Table 12 p -values of the two-level tests under $\mathcal{H}''_{0,second}$

Test	PRNG	N	1st	2nd	3rd	4th	5th
Linear	SHA-1	5,354,000	1.68e-04	3.09e-02	2.41e-01	5.07e-02	5.11e-03
Block Freq.	MT	2,000,000	3.54e-02	2.50e-01	9.63e-01	4.46e-01	7.60e-01
	SHA-1	2,000,000	1.68e-01	3.68e-01	9.02e-01	7.97e-01	6.90e-01
DFT	WELL	100,000	8.97e-01	1.03e-01	9.99e-01	1.87e-01	8.71e-01
	SHA-1	100,000	8.01e-01	9.51e-01	8.82e-01	9.75e-01	5.92e-01

6 Conclusions

In this paper, we study practical upper limits of the sample sizes of the two-level test. With our previous work [5], we derive upper limits of the two-level

test for nine one-level tests in NIST SP800-22. The upper limits proposed in this paper reveals that NIST’s recommendation of the second sample size, the order of the inverse of the significance level, might be misleading: appropriate order of the second sample size strongly depends on the one-level test and the first sample size.

A future work is to derive upper limits or the distributions of approximated p -values of the remaining six one-level tests. Monte Carlo simulation would be suitable for those six tests, but requires a large amount of computation time. To conduct a sufficiently accurate Monte Carlo simulation, we need to compute the p -values of one-level tests more efficiently than the current NIST SP800-22.

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Conflict of interest

The authors declare that they have no conflict of interest.

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